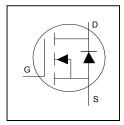




Application

- Brushed Motor drive applications
- **BLDC Motor drive applications**
- Battery powered circuits
- Half-bridge and full-bridge topologies
- Synchronous rectifier applications
- Resonant mode power supplies
- OR-ing and redundant power switches

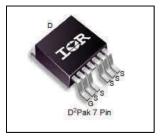
HEXFET® Power MOSFET



V _{DSS}	60V
R _{DS(on)} typ.	1.15m Ω
max	1.4mΩ
D (Silicon Limited)	338A①
D (Package Limited)	240A

Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free, RoHS Compliant



G	D	S
Gate	Drain	Source

Base Part Number	Package Type	Standar	Complete Part Number	
		Form	Quantity	
IRFS7530-7PPbF	D ² Pak-7PIN	Tube	50	IRFS7530-7PPbF
IRF5/550-/PPDF	D Pak-/PIN	Tape and Reel Left	800	IRFS7530TRL7PP

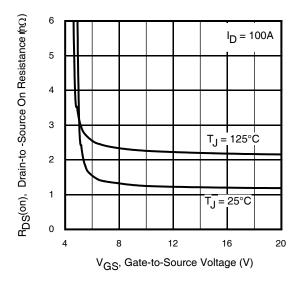


Fig 1. Typical On-Resistance vs. Gate Voltage

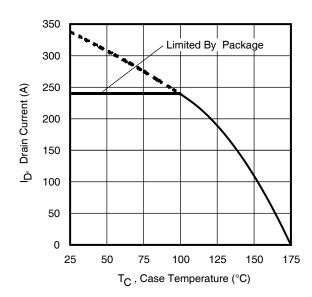


Fig 2. Maximum Drain Current vs. Case Temperature



Absolute Maximium Rating

Symbol	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	338 ①	
I_D @ T_C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	239	Δ.
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Wire Bond Limited)	240	Α
I _{DM}	Pulsed Drain Current ②	1450	
P _D @T _C = 25°C	Maximum Power Dissipation	375	W
	Linear Derating Factor	2.5	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
T _J	Operating Junction and Storage Temperature Range	-55 to + 175	°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Avalanche Characteristics

E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ③	526	m l
E _{AS} (Thermally limited)	Single Pulse Avalanche Energy 9	1029	mJ
I _{AR}	Avalanche Current ②	Coo Fig 14 15 220 22h	Α
E _{AR}	Repetitive Avalanche Energy ②	See Fig 14, 15, 23a, 23b	mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		0.40	°C/W
$R_{\theta JA}$	Junction-to-Ambient ®		40	

Static @ T₁ = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		33		mV/°C	Reference to 25°C, I _D = 1mA ②
R _{DS(on)}	Static Drain-to-Source On-Resistance		1.15	1.4	mΩ	V _{GS} = 10V, I _D = 100A
			1.4		mΩ	$V_{GS} = 6.0V, I_D = 50A$
$V_{GS(th)}$	Gate Threshold Voltage	2.1		3.7	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
DSS	Drain-to-Source Leakage Current			1.0	μΑ	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{V}$
				150		$V_{DS} = 60V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V
R_G	Gate Resistance		2.2		Ω	

Notes:

- Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 240A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. junction temperature.
- Limited by T_{Jmax} , starting T_J = 25°C, L = 105 μ H, R_G = 50 Ω , I_{AS} = 100A, V_{GS} =10V.
- $I_{SD} \le 100A$, di/dt $\le 1575A/\mu s$, $V_{DD} \le V_{(BR)DSS}$, $T_J \le 175$ °C.
- Pulse width $\leq 400\mu s$; duty cycle $\leq 2\%$.
- Coss eff. (TR) is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS.
- © Coss eff. (ER) is a fixed capacitance that gives the same energy as Coss while VDS is rising from 0 to 80% VDSS.
- R_{θ} is measured at T_{J} approximately 90°C.
- Limited by T_{Jmax} , starting $T_J = 25$ °C, L = 1mH, $R_G = 50\Omega$, $I_{AS} = 45A$, $V_{GS} = 10V$.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994: http://www.irf.com/technical-info/appnotes/an-994.pdf



Dynamic Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	249			S	$V_{DS} = 10V, I_{D} = 100A$
Q_g	Total Gate Charge		236	354		I _D = 100A
Q_{gs}	Gate-to-Source Charge		62		nC	V _{DS} = 30V
Q_{gd}	Gate-to-Drain Charge		73		lic	V _{GS} = 10V
Q _{sync}	Total Gate Charge Sync. (Qg - Qgd)		163			
$t_{d(on)}$	Turn-On Delay Time		24			$V_{DD} = 30V$
t _r	Rise Time		102			I _D = 100A
$t_{d(off)}$	Turn-Off Delay Time		168		ns	$R_G = 2.7\Omega$
t _f	Fall Time		79			V _{GS} = 10V⑤
C _{iss}	Input Capacitance		12960			V _{GS} = 0V
C_{oss}	Output Capacitance		1270			V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		760		pF	f = 1.0MHz
Coss eff.(ER)	Effective Output Capacitance (Energy Related)		1248			V _{GS} = 0V, V _{DS} = 0V to 48V⑦
C _{oss eff.(TR)}	Output Capacitance (Time Related)		1590			V _{GS} = 0V, V _{DS} = 0V to 48V⑥

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)①			338①		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			1450	Α	integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.2	V	$T_J = 25^{\circ}C, I_S = 100A, V_{GS} = 0V$ §
dv/dt	Peak Diode Recovery dv/dt⊕		8.5		V/ns	$T_J = 175^{\circ}C, I_S = 100A, V_{DS} = 60V$
4	Payoroo Pagayory Tima		48		no	$T_J = 25^{\circ}C$ $V_{DD} = 51V$
t _{rr}	Reverse Recovery Time		50		ns	$T_J = 125^{\circ}C$ $I_F = 100A$,
0	Dayaraa Dagayary Charga		72		~ C	<u>T_J = 25°C</u> di/dt = 100A/μs ⑤
Q_{rr}	Reverse Recovery Charge		83		nC	<u>T_J = 125°C</u>
I _{RRM}	Reverse Recovery Current		2.5		Α	T _J = 25°C



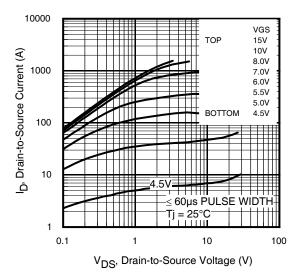


Fig 3. Typical Output Characteristics

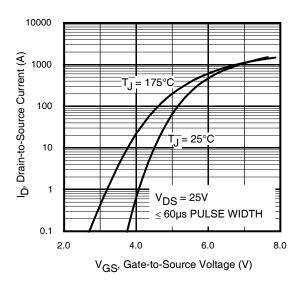


Fig 5. Typical Transfer Characteristics

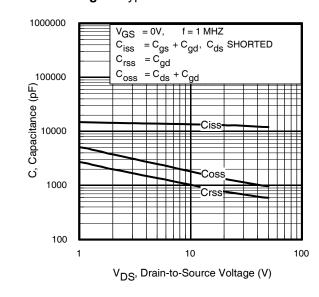


Fig 7. Typical Capacitance vs.

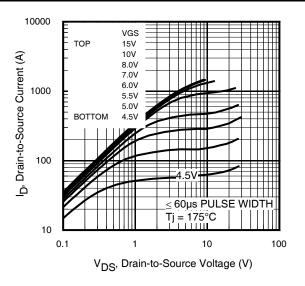


Fig 4. Typical Output Characteristics

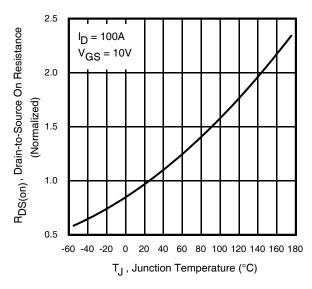


Fig 6. Normalized On-Resistance vs. Temperature

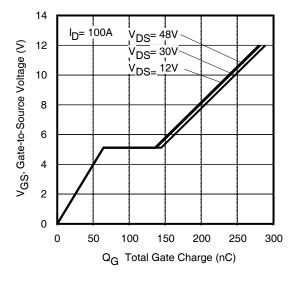


Fig 8. Typical Gate Charge vs. Gate-to-Source Voltage



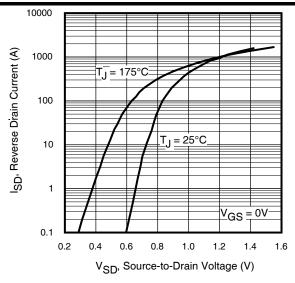


Fig 9. Typical Source-Drain Diode Forward Voltage

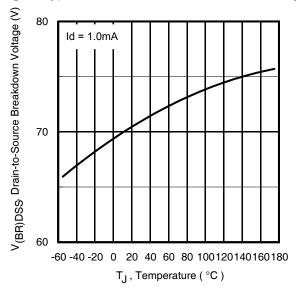


Fig 11. Drain-to-Source Breakdown Voltage

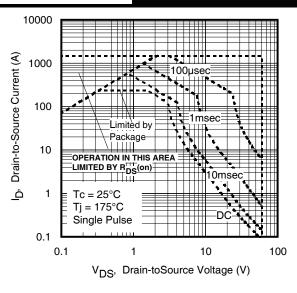


Fig 10. Maximum Safe Operating Area

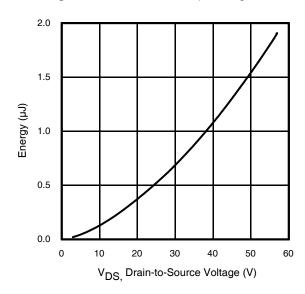


Fig 12. Typical Coss Stored Energy

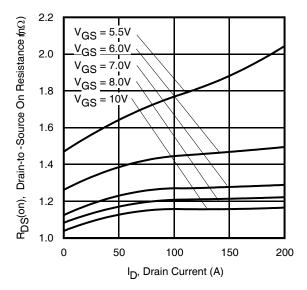


Fig 13. Typical On-Resistance vs. Drain Current



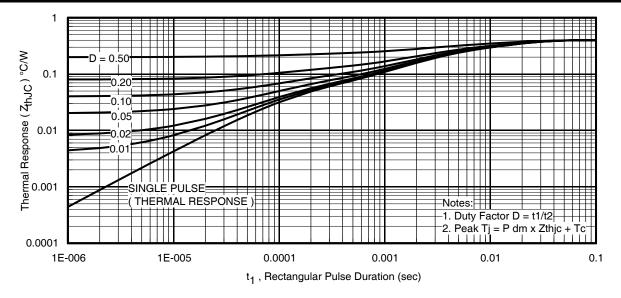


Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case

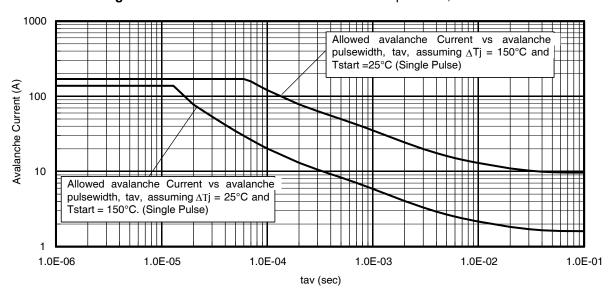


Fig 15. Avalanche Current vs. Pulse Width

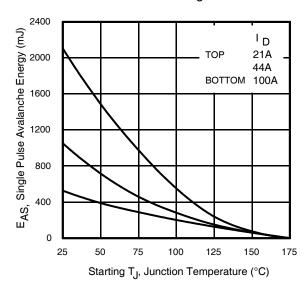


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:

Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.

- 2. Safe operation in Avalanche is allowed as long asT_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 23a, 23b.
- 4. $P_{D (ave)}$ = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).

 t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

 $Z_{th,JC}(D,\,t_{av})$ = Transient thermal resistance, see Figures 13) PD (ave) = 1/2 (1.3·BV·I_{av}) = $\Delta T/Z_{th,JC}$ I_{av} = 2 $\Delta T/$ [1.3·BV· Z_{th}]

 $E_{AS (AR)} = P_{D (ave)} \cdot t_{av}$



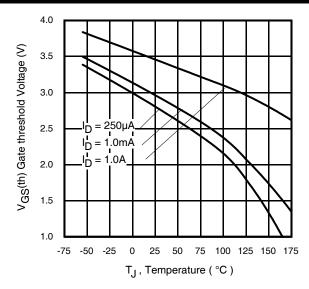


Fig 17. Threshold Voltage vs. Temperature

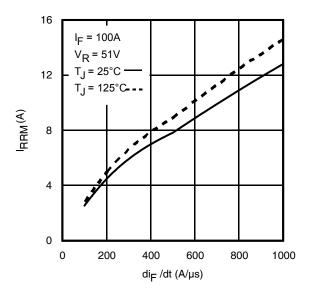


Fig 19. Typical Recovery Current vs. dif/dt

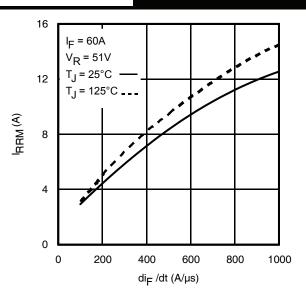


Fig 18. Typical Recovery Current vs. dif/dt

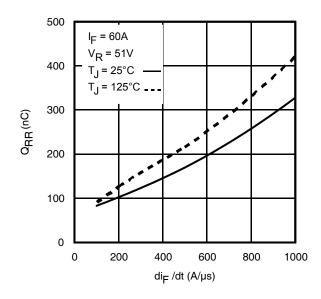


Fig 20. Typical Stored Charge vs. dif/dt

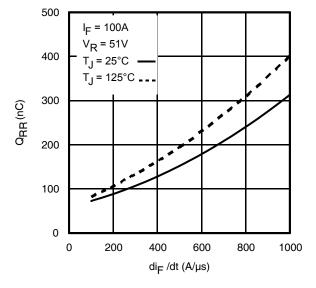


Fig 21. Typical Stored Charge vs. dif/dt



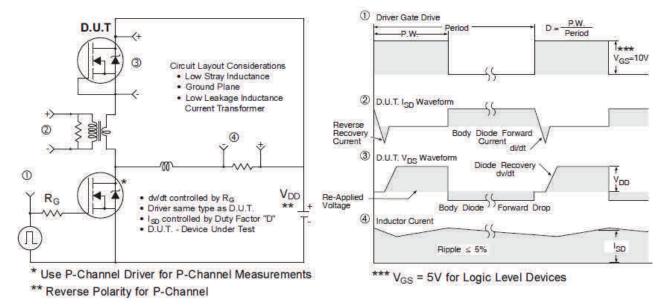


Fig 22. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

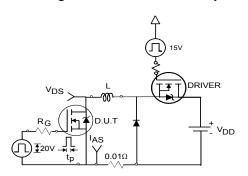


Fig 23a. Unclamped Inductive Test Circuit

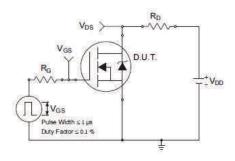


Fig 24a. Switching Time Test Circuit

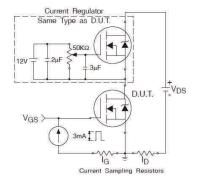


Fig 25a. Gate Charge Test Circuit

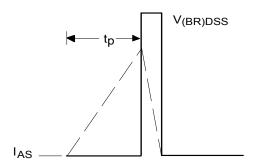


Fig 23b. Unclamped Inductive Waveforms

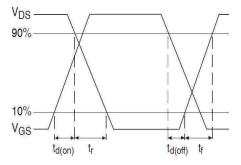


Fig 24b. Switching Time Waveforms

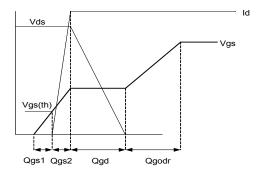
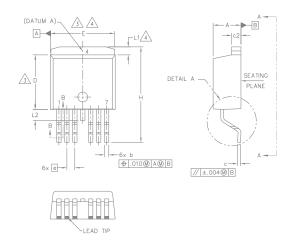
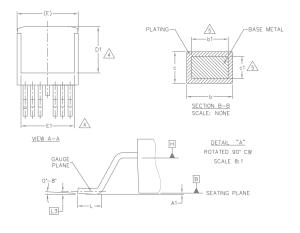


Fig 25b. Gate Charge Waveform



D²Pak-7Pin Package Outline (Dimensions are shown in millimeters (inches))





S Y M	DIMENSIONS				
B	MILLIM	ETERS	INC	HES	O T E S
L	MIN.	MAX.	MIN.	MAX.	S
А	4.06	4.83	.160	.190	
A1	_	0.254	_	.010	
ь	0.51	0.99	.020	.036	
ь1	0.51	0.89	.020	.032	5
С	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	7.42	.270	.292	4
Е	9.65	10.54	.380	.415	3,4
E1	6.22	8.48	.245	.334	4
е	1.27	BSC	.050	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.68	_	.066	4
L2	_	1.78	_	.070	
L3	0.25	BSC	.010	BSC	

NOTES:

- 1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

JA DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

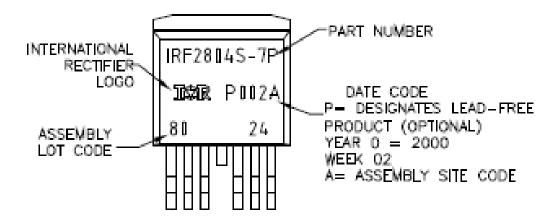
5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- OUTLINE CONFORMS TO JEDEC OUTLINE TO-263CB. EXCEPT FOR DIMS. E, E1 & D1.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



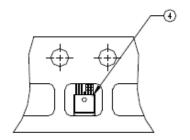
D²Pak-7Pin Part Marking Information



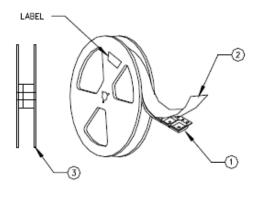
D2Pak-7Pin Tape and Reel

NOTES, TAPE & REEL, LABELLING:

- 1, TAPE AND REEL,
 - 1.1 REEL SIZE 13 INCH DIAMETER.
 - 1.2 EACH REEL CONTAINING 800 DEVICES.
 - 1.3 THERE SHALL BE A MINIMUM OF 42 SEALED POCKETS CONTAINED IN THE LEADER AND A MINIMUM OF 15 SEALED POCKETS IN THE TRAILER.
 - 1.4 PEEL STRENGTH MUST CONFORM TO THE SPEC. NO. 71-9667.
 - 1.5 PART ORIENTATION SHALL BE AS SHOWN BELOW.
 - 1.6 REEL WAY CONTAIN A MAXIMUM OF TWO UNIQUE LOT CODE/DATE CODE COMBINATIONS. REWORKED REELS MAY CONTAIN A MAXIMUM OF THREE UNIQUE LOT CODE/DATE CODE COMBINATIONS. HOWEVER, THE LOT CODES AND DATE CODES WITH THEIR RESPECTIVE QUANTITIES SHALL APPEAR ON THE BAR CODE LABEL FOR THE AFFECTED REEL.



- 2. LABELLING (REEL AND SHIPPING BAG).
 - 2.1 CUST. PART NUMBER (BAR CODE): IRFXXXXSTRL-7P
 - 2.2 CUST. PART NUMBER (TEXT CODE): IRFXXXXSTRL-7P
 - 2.3 I.R. PART NUMBER: IRFXXXXSTRL-7P
 - 2.4 QUANTITY:
 - 2.5 VENDOR CODE; IR
 - 2.6 LOT CODE:
 - 2.7 DATE CODE:



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information[†]

Qualification Level	Industrial (per JEDEC JESD47F) ^{††}				
Moisture Sensitivity Level	D ² Pak-7Pin MSL1 (per JEDEC J-STD-020D ^{††})				
RoHS Compliant	Yes				

- † Qualification standards can be found at International Rectifier's web site: http://www.irf.com/product-info/reliability/
- †† Applicable version of JEDEC standard at the time of product release.

Revision History

Date	Comment
03/05/2015	 Updated E_{AS (L=1mH)} = 1029mJ on page 2 Updated note 9 "Limited by T_{Jmax}, starting T_J = 25°C, L = 1mH, R_G = 50Ω, I_{AS} = 45A, V_{GS} =10V" on page 2 Updated package outline on page 9 .



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To contact International Rectifier, please visit http://www.irf.com/whoto-call/

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